

Mon	Tue				Wed				Thu				Fri								
	8 30	Tut_4 (D)		Tut_5 (E)		8 30	Pow_I (A)			8 30	EOBT_I (A)		8 45	ESD (A)		8 30	Int_I (B)				
		Tut_4		Tut_5		9 10	Pow		Die_RCJ (B)	9 10	EOBT		9 10	ESD		9 10	INT				
	10 30	Tut_4		Tut_5		9 35	Pow		Die	9 35	EOBT		9 35	ESD		9 35	INT				
		Break				10 0	Pow		Die	10 0	EOBT		10 0	ESD		10 0	INT				
	11 0	Opening (A)					Break					Break					Break				
	11 25	Keynote Speech (A)				10 55	Pow		Die_IPFA	10 55	EOBT		DCM (B)	10 55	TCAD (A)						
	12 20					11 20	Pow		Die	11 20	EOBT		DCM	11 20	TCAD						
						11 45	Pow		Die	11 45	EOBT		DCM	11 45	TCAD						
						12 10	Pow		Die	12 10	EOBT		DCM	12 10	TCAD						
						12 35					12 35					12 35	Closing + BP Award (A)				
																12 50					
	Lunch				Lunch				Lunch												
13 30	Tut_1 (D)		Tut_2 (E)		14 15	Asbl (A)			14 15	Fa (A)		Hc_IRPS (B)		Networking Event and Gala Dinner							
15 30	Tut_1		Tut_2		14 40	Asbl		14 30	Comp_I (B)		14 40	Fa		Hc		Tut_1		Tutorial Tcad for Reliability			
	Break				15 5	Asbl		15 5	Comp		15 5	Fa		Hc		Tut_2		Tutorial Defect localization			
16 0	Tut_1 (D)		Tut_3 (E)		15 30	Asbl		15 30	Comp		15 30	Fa		Hc		Tut_3		Tutorial Scanning Probe			
18 0	Tut_1		Tut_3		15 55	Asbl		15 55	Comp		15 55	Fa		Hc		Tut_4		Tutorial Virtual Rel Qualif.			
	Break					Break					Break										
	16 50	Asbl		16 50	Comp		16 50	Fa			Fa				Asbl				Assembly Reliability		
	17 15	Asbl				17 15	Fa				Fa				Comp				Compound Reliability		
	17 40					17 40	Fa				Fa				Pow				Power Devices Reliability		
						18 5									Die				Dielectrics Reliability		
	18 0	Poster (F)		Reception (F)		18 10	Wshop (A)		Wshop (B)		18 10	Wshop (A)		Wshop (B)		Fa				Failure Analysis	
	19 30	Session		Party		19 40	Power		Eufanet		19 40	Power		Eufanet		Hc				Hot Carriers Reliability	
																Eobt				El. Opt. Beam Testing	
																Dcm				Devices, Circuits, MEMs	
																Esd				Electrostatic Discharges	
																Tcad				Tcad for Reliability	